L Number	Hits	Search Text	Ds	Time stamp
1	155570	(resistance) with (temperature)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 08: 42
2	14471	((short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting") and (open-circuit or open-circuits or open-circuited or open-circuiting or "open circuit" or "open circuits" or "open circuited" or "open circuiting"))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 08:43
3	976	((short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting") and (open-circuit or open-circuits or open-circuited or open-circuiting or "open circuit" or "open circuits" or "open circuited" or "open circuiting")) and ((resistance) with (temperature))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 08:45
4	53	<pre>((short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting") and (open-circuit or open-circuits or open-circuited or open-circuiting or "open circuit" or "open circuits" or "open circuited" or "open circuiting")) and ((resistance) with (temperature or</pre>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 09:51
5	13993	degree or degrees) with (plot or plots or plotted or plotting or graph or graphs or graphed or graphing or table or tables)) "shape memory alloy" or "shape memory alloys"	USPAT; US-PGPUB; EPO; JPO; DERWENT;	2003/09/15 08:59
6	0	("shape memory alloy" or "shape memory alloys") with "multi-chip package"	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 08:59
7	0	("shape memory alloy" or "shape memory alloys") same "multi-chip package"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/09/15 08:59
8	3	("shape memory alloy" or "shape memory alloys") and "multi-chip package"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/09/15 08:59
9	45	("shape memory alloy" or "shape memory alloys") same ("integrated circuit" or "integrated circuits")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/09/15 09:00
10	283	((resistance) with (temperature or degree or degrees) with (plot or plots or plotted or plotting or graph or graphs or graphed or graphing or table or tables)) same (epoxy or resin or resins)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 10:53

Search History 9/15/03 5:18:03 PM Page 1

11	312	((resistance) with (temperature or degree	USPAT;	2003/09/15
		or degrees) with (plot or plots or	US-PGPUB;	09:06
	ł	plotted or plotting or graph or graphs or	EPO; JPO;	
		graphed or graphing or table or tables))	DERWENT;	
1		same (epoxy or resin or resins or solder	IBM TDB	
1		or solders)	1011_100	
10			,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,	2002/00/15
12	0	, , , = - =	USPAT;	2003/09/15
		or degrees) with (plot or plots or	US-PGPUB;	09:08
		plotted or plotting or graph or graphs or	EPO; JPO;	
1	1	graphed or graphing or table or tables))	DERWENT;	
ļ		same (epoxy or resin or resins or solder	IBM_TDB	
1		or solders) same ((short-circuit or		
		short-circuits or short-circuited or		
		short-circuiting or "short circuit" or		
		"short circuits" or "short circuited" or		
		"short circuiting") and (open-circuit or		
		open-circuits or open-circuited or		
		open-circuiting or "open circuit" or		
	-	"open circuits" or "open circuited" or	-	
		"open circuiting"))	•	
12	110	open circuiting //	USPAT;	2002/00/15
13	110	POTUET_TELLOM .	USPAT; US-PGPUB;	2003/09/15
			l	09:08
			EPO; JPO;	
			DERWENT;	
	5.470		IBM_TDB	0000/00/15
14	5478	solder-reflow or "solder reflow" or	USPAT;	2003/09/15
		solder/reflow or solder-re-flow or	US-PGPUB;	09:11
		"solder re-flow" or solder/re-flow	EPO; JPO;	
			DERWENT;	
1		l	IBM_TDB	
15	198	(solder-reflow or "solder reflow" or	USPAT;	2003/09/15
		solder/reflow or solder-re-flow or	US-PGPUB;	09:52
		"solder re-flow" or solder/re-flow) with	EPO; JPO;	
		(test or testing or tested or tester or	DERWENT;	
		testers or tests)	IBM_TDB	
24	173	cole.in. and epoxy	USPAT;	2003/09/15
			US-PGPUB;	09:18
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
25	97	sandia.asn. and epoxy	USPAT;	2003/09/15
			US-PGPUB;	09:20
			EPO; JPO;	
			DERWENT;	
1			IBM_TDB	
26	11	sandia.asn. and cole.in.	USPAT;	2003/09/15
			US-PGPUB;	09:20
1			EPO; JPO;	
1			DERWENT;	
			IBM_TDB	
27	4	("5422498"   "5430305"   "5708371"	USPAT	2003/09/15
		"5844416").PN.		09:24
28	22	5422498.URPN.	USPAT	2003/09/15
				09:25
29	3	("4874251"   "5042952"   "5049811").PN.	USPAT	2003/09/15
				09:25
30	1	"4698587".PN.	USPAT	2003/09/15
				09:33
31	3	((solder-reflow or "solder reflow" or	USPAT;	2003/09/15
		solder/reflow or solder-re-flow or	US-PGPUB;	10:01
		"solder re-flow" or solder/re-flow) with	EPO; JPO;	
		(test or testing or tested or tester or	DERWENT;	
		testers or tests)).ti.	IBM_TDB	

F-20				10000/00/15
32		(solder-reflow or "solder reflow" or	USPAT;	2003/09/15
		solder/reflow or solder-re-flow or	US-PGPUB;	10:01
		"solder re-flow" or solder/re-flow) with	EPO; JPO;	
		(test or testing or tested or tester or	DERWENT;	
		testers or tests) and ((short-circuit or	IBM_TDB	
		short-circuits or short-circuited or		
	-	short-circuiting or "short circuit" or		
		"short circuits" or "short circuited" or		
	]	"short circuiting") and (open-circuit or open-circuits or open-circuited or		
		open-circuits of open-circuited of open-circuiting or "open circuit" or		
		"open circuits" or "open circuit or		
		"open circuiting"))		
33	283	((solder-reflow or "solder reflow" or	USPAT;	2003/09/15
33	203	solder/reflow or solder-re-flow or	US-PGPUB;	10:01
		"solder re-flow" or solder/re-flow)).ti.	EPO; JPO;	10.01
		solder to from or solder, to from, , . et.	DERWENT;	
			IBM TDB	
34	1	(solder-reflow or "solder reflow" or	USPAT;	2003/09/15
• •	-	solder/reflow or solder-re-flow or	US-PGPUB;	10:50
		"solder re-flow" or solder/re-flow).ti.	EPO; JPO;	
	·	and ((short-circuit or short-circuits or	DERWENT;	
		short-circuited or short-circuiting or	IBM TDB	
		"short circuit" or "short circuits" or	_	
		"short circuited" or "short circuiting")	ŀ	
		and (open-circuit or open-circuits or		
		open-circuited or open-circuiting or		i
j		"open circuit" or "open circuits" or		
		"open circuited" or "open circuiting"))		
35	0	,,	USPAT;	2003/09/15
		short-circuited or short-circuiting or	US-PGPUB;	10:51
		"short circuit" or "short circuits" or	EPO; JPO;	
		"short circuited" or "short circuiting")	DERWENT;	
		and (open-circuit or open-circuits or	IBM_TDB	
		open-circuited or open-circuiting or		
		"open circuit" or "open circuits" or		
		"open circuited" or "open circuiting"))		
36	173	with "change in resistance" "wiring defects"	USPAT;	2003/09/15
30	1/3	willing delects	US-PGPUB;	10:52
			EPO; JPO;	10.52
	ĺ		DERWENT;	
			IBM TDB	
37	lol	"wiring defects" and ((resistance or	USPAT;	2003/09/15
		resistence or resistivity or	US-PGPUB;	10:53
		resistivities) with (temperature or	EPO; JPO;	
		degree or degrees) with (plot or plots or	DERWENT;	
		plotted or plotting or graph or graphs or	IBM_TDB	
		graphed or graphing or table or tables))		
38	5522	((resistance or resistence or resistivity	USPAT;	2003/09/15
		or resistivities) with (temperature or	US-PGPUB;	10:54
		degree or degrees) with (plot or plots or	EPO; JPO;	
		plotted or plotting or graph or graphs or	DERWENT;	
30		graphed or graphing or table or tables))	IBM_TDB	2002/00/15
39	0	,,	USPAT;	2003/09/15
		or resistivities) with (temperature or degree or degrees) with (plot or plots or	US-PGPUB; EPO; JPO;	10:54
		plotted or plotting or graph or graphs or	DERWENT;	
		graphed or graphing or table or tables))	IBM TDB	
		same ((short-circuit or short-circuits or	1011_100	
		short-circuited or short-circuiting or		
		"short circuit" or "short circuits" or		
		"short circuited" or "short circuiting")		
	1	and (open-circuit or open-circuits or		
		open-circuited or open-circuiting or		
		"open circuit" or "open circuits" or		
	l i	"open circuited" or "open circuiting"))	I	1

41	151	((resistance or resistence or resistivity or resistivities) with (temperature or degree or degrees) with (plot or plots or plotted or plotting or graph or graphs or graphed or graphing or table or tables)) same ((short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting") and (open-circuit or open-circuits or open-circuited or open-circuits or "open circuit" or "open circuits" or "open circuits" or "open circuited" or "open circuiting")) or ((short or shorted or open or opened) with (circuit or circuits or circuited or circuited))) "reflow test" or "reflow tests" or	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 11:00
	:	"reflow testing" or "reflow tested" or  "re-flow test" or "re-flow tests" or  "re-flow testing" or "re-flow tested"	US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	11:08
42	480	"temperature cycle test"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/09/15 11:09
43	1	"temperature cycle test".ti.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/09/15 11:10
44	568	"temperature cycle test" or "temperature-cycle test" or "temperature cycle tested" or "temperature-cycle tested" or "temperature cycle testing" or "temperature-cycle testing" or "temperature cycle tests" or "temperature-cycle tests"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 12:23
45	2	("4,695,404").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 11:11
46	20	("temperature cycle test" or "temperature-cycle test" or "temperature cycle tested" or "temperature-cycle tested" or "temperature cycle testing" or "temperature-cycle testing" or "temperature cycle tests" or "temperature-cycle tests") and ((resistance or resistence or resistivity or resistivities) with (temperature or degree or degrees) with (plot or plots or plotted or plotting or graph or graphs or graphed or graphing or table or tables))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 11:13

				· · · · · · · · · · · · · · · · · · ·
48	3	("temperature cycle test" or	USPAT;	2003/09/15
1		"temperature-cycle test" or "temperature	US-PGPUB;	11:22
		cycle tested" or "temperature-cycle	EPO; JPO;	
		tested" or "temperature cycle testing" or	DERWENT;	
		"temperature-cycle testing" or	IBM TDB	
			1 1 1 1 1 1 1 1	
		"temperature cycle tests" or		
		"temperature-cycle tests") and		
		(((short-circuit or short-circuits or		
		short-circuited or short-circuiting or		
		"short circuit" or "short circuits" or		
		"short circuited" or "short circuiting")		
				2
		and (open-circuit or open-circuits or		
		open-circuited or open-circuiting or		
		"open circuit" or "open circuits" or		
	i	"open circuited" or "open circuiting"))		
		or (((short or shorted) and (open or		
		opened)) with (circuit or circuits or		
		circuited or circuited)))		
1.5	105			0000 (00 (15
47	125	("temperature cycle test" or	USPAT;	2003/09/15
		"temperature-cycle test" or "temperature	US-PGPUB;	11:23
		cycle tested" or "temperature-cycle	EPO; JPO;	
	[	tested" or "temperature cycle testing" or	DERWENT;	
		"temperature-cycle testing" or	IBM TDB	
		"temperature cycle tests" or		
	[			
	[	"temperature-cycle tests") and		
		(((short-circuit or short-circuits or		
		short-circuited or short-circuiting or		
		"short circuit" or "short circuits" or		
		"short circuited" or "short circuiting")		
		and (open-circuit or open-circuits or		
	}	open-circuited or open-circuiting or		
		"open circuit" or "open circuits" or		
1		"open circuit, or open circuits or		
		"open circuited" or "open circuiting"))		
	Į.	or ((short or shorted or open or opened)		
ļ		with (circuit or circuits or circuited or		
		circuited)))		
50	5500	"temperature cycling"	USPAT;	2003/09/15
		Jompoza Jazzing	US-PGPUB;	11:47
				11.3/
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
49.	1	"temperature cyclying"	USPAT;	2003/09/15
			US-PGPUB;	11:46
			EPO; JPO;	
			DERWENT;	
F 1			IBM_TDB	2002/00/15
51	2	"temperature cycling" and ((resistance or	USPAT;	2003/09/15
		resistence or resistivity or	US-PGPUB;	11:49
		resistivities) with (temperature or	EPO; JPO;	
		degree or degrees) with (plot or plots or	DERWENT;	
	[	plotted or plotting or graph or graphs or	IBM TDB	
	[	graphed or graphing or table or tables))		
		same (((short-circuit or short-circuits		
		or short-circuited or short-circuiting		1
}				1
	1	or "short circuit" or "short circuits" or		1
		"short circuited" or "short circuiting")		
		and (open-circuit or open-circuits or		ļ
		open-circuited or open-circuiting or		
		"open circuit" or "open circuits" or		
	[	"open circuited" or "open circuiting"))		
		or ((short or shorted or open or opened)		1
				1
	j	with (circuit or circuits or circuited or		1
1		circuited)))		
52	67	"temperature cycling" and ((resistance or	USPAT;	2003/09/15
	1	resistence or resistivity or	US-PGPUB;	12:11
		resistivities) with (temperature or	EPO; JPO;	
	]	degree or degrees) with (plot or plots or	DERWENT;	
	]		1	
		plotted or plotting or graph or graphs or	IBM_TDB	
1	1	graphed or graphing or table or tables))		

54	0	espec.asn. and "solder connections"	USPAT;	2003/09/15
			US-PGPUB;	12:11
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
55	0	espec.asn. and solder	USPAT;	2003/09/15
			US-PGPUB;	12:22
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
56	2	("5920504").PN.	USPAT;	2003/09/15
			US-PGPUB;	12:23
			EPO; JPO;	
			DERWENT;	
			IBM TDB	
57	2	("5902504").PN.	USPAT;	2003/09/15
			US-PGPUB;	12:23
			EPO; JPO;	
			DERWENT;	
	1		IBM TDB	
58	2	("temperature cycle test" or	USPAT;	2003/09/15
	-	"temperature-cycle test" or "temperature	US-PGPUB;	12:26
Ì		cycle tested" or "temperature-cycle	EPO; JPO;	12.23
		tested" or "temperature cycle testing" or	DERWENT;	
1		"temperature-cycle testing" or	IBM TDB	
		"temperature-cycle testing of "temperature cycle tests" or	1011_100	
		"temperature cycle tests" or "temperature-cycle tests") with		
		(continuous or continuously)		
59	o		IICDAM.	2002/00/15
39	١	("temperature cycle test" or	USPAT;	2003/09/15
		"temperature-cycle test" or "temperature	US-PGPUB;	13:37
		cycle tested" or "temperature-cycle	EPO; JPO;	
		tested" or "temperature cycle testing" or	DERWENT;	
		"temperature-cycle testing" or	IBM_TDB	
		"temperature cycle tests" or		
	015	"temperature-cycle tests") and espec.asn.		0000 (00 (15
53	815	espec.asn.	USPAT;	2003/09/15
			US-PGPUB;	13:18
			EPO; JPO;	
-			DERWENT;	
			IBM_TDB	
60	51487	ishii.in.	USPAT;	2003/09/15
			US-PGPUB;	13:18
			EPO; JPO;	
1			DERWENT;	
			IBM_TDB	
61	403	ishii.in. and solder	USPAT;	2003/09/15
			US-PGPUB;	13:18
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
62	7	("temperature cycle test" or	USPAT;	2003/09/15
		"temperature-cycle test" or "temperature	US-PGPUB;	14:42
		cycle tested" or "temperature-cycle	EPO; JPO;	
		tested" or "temperature cycle testing" or	DERWENT;	
		"temperature-cycle testing" or	IBM_TDB	
		"temperature cycle tests" or	_	
		"temperature-cycle tests") with		
		(short-circuit or short-circuits or		
		short-circuited or short-circuiting or		
		"short circuit" or "short circuits" or		
		"short circuited" or "short circuiting")		
64	162	702/99.ccls.	USPAT;	2003/09/15
			US-PGPUB;	14:50
			EPO; JPO;	
			DERWENT;	
			IBM TDB	
65	545	702/117.ccls.	USPAT;	2003/09/15
			US-PGPUB;	14:50
			EPO; JPO;	
			DERWENT;	
			IBM TDB	
L	L		I DEL I DE	L

Search History

9/15/03 5:18:03 PM Page 6

66	144	702/118.ccls.	USPAT;	2003/09/15
			US-PGPUB;	14:50
			EPO; JPO;	
			DERWENT;	
			IBM TDB	Í
67	140	702/119.ccls.	USPAT;	2003/09/15
			US-PGPUB;	14:50
			EPO; JPO;	
			DERWENT;	
1			IBM TDB	
68	127	702/120.ccls.	USPAT;	2003/09/15
"	12,	/ 120.0013.	US-PGPUB;	14:50
				14.50
			EPO; JPO;	
			DERWENT;	
69	536	702/1201-	IBM_TDB	2002/00/15
69	536	702/130.ccls.	USPAT;	2003/09/15
			US-PGPUB;	14:50
			EPO; JPO;	İ
			DERWENT;	l i
		500/400	IBM_TDB	
70	61	702/133.ccls.	USPAT;	2003/09/15
			US-PGPUB;	14:50
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
71	67	702/134.ccls.	USPAT;	2003/09/15
			US-PGPUB;	14:50
			EPO; JPO;	]
1			DERWENT;	
1			IBM_TDB	
72	39	702/135.ccls.	USPAT;	2003/09/15
			US-PGPUB;	14:50
	-		EPO; JPO;	
			DERWENT;	
			IBM TDB	
73	250	702/136.ccls.	USPAT;	2003/09/15
			US-PGPUB;	14:50
			EPO; JPO;	
			DERWENT;	<u> </u>
			IBM TDB	ļ.
74	152	324/703.ccls.	USPAT;	2003/09/15
			US-PGPUB;	14:50
			EPO; JPO;	
			DERWENT;	
			IBM TDB	
75	529	324/760.ccls.	USPAT;	2003/09/15
		·	US-PGPUB;	14:50
			EPO; JPO;	
			DERWENT;	
			IBM TDB	
76	235	(702/99.ccls. 702/117.ccls. 702/118.ccls.	USPAT;	2003/09/15
' -		702/119.ccls. 702/120.ccls. 702/130.ccls.	US-PGPUB;	14:56
]		702/133.ccls. 702/134.ccls. 702/135.ccls.	EPO; JPO;	
		702/136.ccls. 324/703.ccls.	DERWENT;	1
		324/760.ccls.) and @pd>=20030201	IBM TDB	
77	ا م ا	("5,419,780").PN.	USPAT;	2003/09/15
' '		( 5, 225, 100 )	US-PGPUB;	15:11
			EPO; JPO;	
1			DERWENT;	
j			IBM TDB	
78	713	(Peltier-junction or peltier) and	USPAT;	2003/09/15
, ' · ·	113	(heatsink or heat-sink or "heat sink" or	US-PGPUB;	15:12
		heatsinks or heat-sinks or "heat sinks")		13.14
			EPO; JPO;	
		and (fan or fans)	DERWENT;	
170	, ,,	(Doltion inpution on malting)	IBM_TDB	2003/00/15
79	274		USPAT;	2003/09/15
ļ		(heatsink or heat-sink or "heat sink" or	US-PGPUB;	15:12
		heatsinks or heat-sinks or "heat sinks")	EPO; JPO;	1
		same (fan or fans)	DERWENT;	
	l		IBM_TDB	

			<b>(</b>	
80	6	(Peltier-junction or peltier) same	USPAT;	2003/09/15
		(heatsink or heat-sink or "heat sink" or	US-PGPUB;	15:14
		heatsinks or heat-sinks or "heat sinks")	EPO; JPO;	
		same (fan or fans) same (program or	DERWENT;	
		programs or programmed or programming)	IBM TDB	
81	274			2002/00/15
91	274	1 '	USPAT;	2003/09/15
		(heatsink or heat-sink or "heat sink" or	US-PGPUB;	15:15
		heatsinks or heat-sinks or "heat sinks")	EPO; JPO;	
		same (fan or fans)	DERWENT;	
			IBM_TDB	
82	58	((Peltier-junction or peltier) same	USPAT;	2003/09/15
		(heatsink or heat-sink or "heat sink" or	US-PGPUB;	15:36
		heatsinks or heat-sinks or "heat sinks")	EPO; JPO;	
		same (fan or fans)) and (pcb or	DERWENT;	
		circuit-board or circuit-boards or	IBM TDB	
		"circuit board" or "circuit boards")	10.1_100	
100	١ ,		TICDAM -	2002/00/15
83	2	("5,457,342").PN.	USPAT;	2003/09/15
İ			US-PGPUB;	15:29
			EPO; JPO;	
			DERWENT;	
	1		IBM_TDB	
84	2	("4,685,081").PN.	USPAT;	2003/09/15
[			US-PGPUB;	15:29
1			EPO; JPO;	
			DERWENT;	
			IBM TDB	
85	27	(((Peltier-junction or peltier) same	USPAT;	2003/09/15
03	"	(heatsink or heat-sink or "heat sink" or	US-PGPUB;	15:57
		heatsinks or heat-sinks or "heat sinks")		13.37
			EPO; JPO;	
		same (fan or fans)) and (pcb or	DERWENT;	l i
:		circuit-board or circuit-boards or	IBM_TDB	
		"circuit board" or "circuit boards")) and		
	1	(program or programs or programmed or		
	İ	programming or programmable)		
86	1	("5107325").PN.	USPAT;	2003/09/15
			US-PGPUB;	15:57
	1		EPO; JPO;	
	ľ		DERWENT;	
			IBM TDB	
l <b>-</b>	2	("4576322").PN.	USPAT;	2003/09/15
		( 10,0022 , 12.11	US-PGPUB;	08:41
			EPO; JPO;	00.41
			DERWENT;	
	10557		IBM_TDB	2002/02/12
-	12557	peltier	USPAT;	2003/02/12
			US-PGPUB;	15:26
[			EPO; JPO;	
İ	1		DERWENT;	
	1	l	IBM_TDB	/
-	5	peltier-junction	USPAT;	2003/02/12
	1		US-PGPUB;	15:26
]			EPO; JPO;	
	1		DERWENT;	
	1		IBM TDB	
-	113	("integrated circuit" or "integrated	USPAT;	2003/02/12
	1	circuits" or "ic" or "ics" or "ic's").ti.	US-PGPUB;	15:28
	1	and peltier	EPO; JPO;	
	1		DERWENT;	
			IBM TDB	
l _	.ه	(("integrated circuit" or "integrated	USPAT;	2003/02/12
		direction or "in" or "ine" or "integrated	F '	
	1	circuits" or "ic" or "ics" or "ic's") and	US-PGPUB;	15:30
	1	(test or tests or testing or tested or	EPO; JPO;	
		tester or tester)).ti. and peltier	DERWENT;	
	[		IBM_TDB	l i
-	375	(("integrated circuit" or "integrated	USPAT;	2003/02/12
		circuits" or "ic" or "ics" or "ic's") and	US-PGPUB;	15:31
1		(test or tests or testing or tested or	EPO; JPO;	
		tester or tester)) and peltier	DERWENT;	
		,, •	IBM TDB	
t	1	1	,	

_	83	(("integrated circuit" or "integrated circuits" or "ic" or "ics" or "ic's") and	USPAT; US-PGPUB;	2003/02/12 15:32
		(test or tests or testing or tested or tester or tester)) and peltier and (fan or fans)	EPO; JPO; DERWENT; IBM_TDB	
<b>-</b> 	0	(("integrated circuit" or "integrated circuits" or "ic" or "ics" or "ic's") and (test or tests or testing or tested or tester or tester)) and peltier and (fan	USPAT; US-PGPUB; EPO; JPO;	2003/02/12 15:32
		or fans) and ("power bus" or "power busses")	DERWENT; IBM_TDB	2002/02/12
_	0	(("integrated circuit" or "integrated circuits" or "ic" or "ics" or "ic's") and (test or tests or testing or tested or tester or tester)) and peltier and ("power bus" or "power busses") and	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/12 15:33
-	3	circuits" or "ic" or "ics" or "ic's") and (test or tests or testing or tested or tester or tester)) and peltier and	USPAT; US-PGPUB; EPO; JPO; DERWENT;	2003/02/12 15:33
-	0	<pre>("power bus" or "power busses") (("integrated circuit" or "integrated circuits" or "ic" or "ics" or "ic's") same (test or tests or testing or tested or tester or tester)) and (power with bus</pre>	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2003/02/12 15:34
		with ground with resistance with temperature)	IBM_TDB	
-	0	circuits" or "ic" or "ics" or "ic's") same (test or tests or testing or tested or tester or tester)) and (bus with	USPAT; US-PGPUB; EPO; JPO; DERWENT;	2003/02/12 15:35
_	o	ground with resistance with temperature) "power bus to ground"	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2003/02/12 15:35
_	141	"power bus" with resistance	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/02/12 15:37
-	4	("power bus" with resistance) same temperature	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/02/12 15:39
_	293	(bus with resistance) same temperature	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/02/12 15:39
-	152	(bus with resistance) with temperature	USPAT; US-PGPUB; EPO; JPO; DERWENT;	2003/02/12 16:42
_	29	("3979671"   "3986337"   "4089184"   "4134447"   "4172993"   "4253515"   "4324285"   "4402185"   "4426619"   "4579527"   "4604572"   "4607220"   "4612772"   "4636726"   "4727720"   "4734872"   "4759190"   "4780086"   "4839587"   "5006796"   "5028988"   "5184068"   "5424209"   "5510724"   "5767489"   "5844208"   "5903163"   "5966940"   "6095293").PN.	IBM_TDB USPAT	2003/02/12 15:50

-	53	"power bus" with temperature	USPAT;	2003/02/12
			US-PGPUB;	16:44
			EPO; JPO;	
	i		DERWENT;	
			IBM_TDB	
	2	"power bus" with temperatures	USPAT;	2003/02/12
			US-PGPUB;	16:43
			EPO; JPO;	
			DERWENT;	
	·		IBM_TDB	
-	0	"power buses" with temperatures	USPAT;	2003/02/12
	1		US-PGPUB;	16:43
İ			EPO; JPO;	
1			DERWENT;	•
				1
			IBM_TDB	
-	13	"power buses" with temperature	USPAT;	2003/02/12
			US-PGPUB;	16:43
į			EPO; JPO;	
			DERWENT;	
			IBM TDB	
	_	"norrow hugod" with dogress	_	2003/02/12
-	1	"power buses" with degrees	USPAT;	
			US-PGPUB;	16:44
	1		EPO; JPO;	
	1		DERWENT;	
	1		IBM TDB	Į i
_	2	"power buses" with degree	USPAT;	2003/02/12
		ponor suses wrom degree	US-PGPUB;	16:44
	1			10.44
			EPO; JPO;	
	1		DERWENT;	
1			IBM_TDB	
_	13	"power bus" with degree	USPAT;	2003/02/12
1			US-PGPUB;	16:44
			EPO; JPO;	
			1	
			DERWENT;	
	_		IBM_TDB	
-	2	"power bus" with degrees	USPAT;	2003/02/12
			US-PGPUB;	16:44
			EPO; JPO;	
			DERWENT;	
	}		IBM TDB	
	80	"marrow hora" with tomposature) ("narrow	_	2003/02/13
-	00	"power bus" with temperature) ("power	USPAT;	
		bus" with temperatures) ("power buses"	US-PGPUB;	07:50
		with temperatures) ("power buses" with	EPO; JPO;	
	1	temperature) ("power buses" with degrees)	DERWENT;	
	1	("power buses" with degree) ("power bus"	IBM TDB	
	1	with degree) ("power bus" with degrees	_	į i
l -	5345	bus with temperature) (bus with	USPAT;	2003/02/13
	03.3	temperatures) (buses with temperatures)	US-PGPUB;	07:55
	1		1	07.33
		(buses with temperature) (buses with	EPO; JPO;	
	1	degrees) (buses with degree) (bus with	DERWENT;	
	1	degree) (bus with degrees	IBM_TDB	
-	5345	bus with temperature) (bus with	USPAT;	2003/02/13
	1	temperatures) (buses with temperatures)	US-PGPUB;	07:58
	1	(buses with temperature) (buses with	EPO; JPO;	
		degrees) (buses with degree) (bus with	DERWENT;	
ŀ	1		IBM TDB	
	1	degree) (bus with degrees	_	2002/00/12
-	1041	((bus with temperature) (bus with	USPAT;	2003/02/13
	1	temperatures) (buses with temperatures)	US-PGPUB;	09:12
		(buses with temperature) (buses with	EPO; JPO;	
	1	degrees) (buses with degree) (bus with	DERWENT;	
	1	degree) (bus with degrees)).ab.	IBM TDB	
_	1827	(plot or plots or plotting or plotted or	USPAT;	2003/02/13
	102,		US-PGPUB;	10:59
		graph or graphs or graphing or graphed)	· ·	10.39
	1	with (temperature or temperatures) with	EPO; JPO;	
		(resistance or resistances)	DERWENT;	
			IBM_TDB	
-	2156	(plot or plots or plotting or plotted or	USPAT;	2003/02/13
		graph or graphs or graphing or graphed)	US-PGPUB;	10:11
		with (temperature or temperatures) with		
	1		EPO; JPO;	
		(voltage or voltages)	DERWENT;	
			IBM_TDB	

	_			
-	0	(plot or plots or plotting or plotted or	USPAT;	2003/02/13
	1	graph or graphs or graphing or graphed)	US-PGPUB;	10:12
		with (temperature or temperatures) with	EPO; JPO;	
		(voltage or voltages) with (bus or	DERWENT;	
		busses)	IBM_TDB	
-	729	((plot or plots or plotting or plotted or	USPAT;	2003/02/13
1.		graph or graphs or graphing or graphed)	US-PGPUB;	10:15
		with (temperature or temperatures) with	EPO; JPO;	
		(voltage or voltages)) and (test or tests	DERWENT;	
		or tested or testing or tester or	IBM TDB	i
		testers)	1511_155	
_	804		USPAT;	2003/02/13
	001	graph or graphs or graphing or graphed)	US-PGPUB;	12:03
		with (temperature or temperatures) with	EPO; JPO;	12.03
		(resistance or resistances)) and (test or	DERWENT;	
		tests or tested or testing or tester or	· ·	
			IBM_TDB	i
:	10	testers)	HCDAM	2002/02/12
-	19	4734641.URPN.	USPAT	2003/02/13
			l	11:52
-	58	"thermal evaluation"	USPAT;	2003/02/13
			US-PGPUB;	12:05
			EPO; JPO;	
			DERWENT;	]
	1		IBM_TDB	
-	10	"3982918"	USPAT;	2003/02/13
			US-PGPUB;	12:05
			EPO; JPO;	
			DERWENT;	
	ļ		IBM TDB	
_	2	("3982918").PN.	USPAT;	2003/02/13
	1		US-PGPUB;	12:05
	İ		EPO; JPO;	
			DERWENT;	
			IBM TDB	
i _	2	("3982218").PN.	USPAT;	2003/02/13
	_	( 3302210 ).IN.	US-PGPUB;	13:25
			EPO; JPO;	13.23
			DERWENT;	
			IBM TDB	
_	7	bus-to-ground	USPAT;	2003/02/13
	/	bus to ground	US-PGPUB;	13:29
			EPO; JPO;	13.23
			DERWENT;	
			IBM TDB	
_	3253	unisys.asn.	USPAT;	2003/02/13
	3233	untaya.aan.		
1	1		US-PGPUB;	13:26
	[		EPO; JPO;	
	1		DERWENT;	
		h	IBM_TDB	2002/02/22
-	5150	bus near3 ground	USPAT;	2003/02/13
			US-PGPUB;	13:32
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
-	13	··· ···	USPAT;	2003/02/13
		) and unisys.asn.	US-PGPUB;	13:30
			EPO; JPO;	
1			DERWENT;	
1			IBM_TDB	j l
-	1	, , , , , , , , , , , , , , , , , , , ,	USPAT;	2003/02/13
	}	) and unisys.asn.	US-PGPUB;	13:30
	1	and temperature	EPO; JPO;	ļ
	1		DERWENT;	
			IBM TDB	
_	12115	bus near3 voltage	USPAT;	2003/02/13
	[	<b>3</b> -	US-PGPUB;	13:32
	1		EPO; JPO;	
			DERWENT;	
	1		IBM TDB	l l
L	J	1	2011 100	l

_	30	(bus near3 voltage) and unisys.asn.	USPAT;	2003/02/13
			US-PGPUB;	13:32
			EPO; JPO;	Į
			DERWENT;	į
			IBM_TDB	
-	1	(bus near3 voltage) and unisys.asn. and	USPAT;	2003/02/13
		temperature	US-PGPUB;	13:32
•		-	EPO; JPO;	
			DERWENT;	
	ł		IBM TDB	
-	1	(bus near3 resistance) and unisys.asn.	USPAT;	2003/02/13
		and temperature	US-PGPUB;	13:33
		1	EPO; JPO;	
			DERWENT;	
			IBM TDB	
_	3	(bus near3 resistance) and unisys.asn.	USPAT;	2003/02/13
		(**************************************	US-PGPUB;	13:37
			EPO; JPO;	
			DERWENT;	
			IBM TDB	
1 _	119	702/118.ccls.	USPAT;	2003/02/13
			US-PGPUB;	13:37
			EPO; JPO;	
			DERWENT;	
			IBM TDB	
_	117	702/119.ccls.	USPAT;	2003/02/13
		,,	US-PGPUB;	13:37
			EPO; JPO;	13.37
			DERWENT;	
			IBM TDB	
_	101	702/120.ccls.	USPAT;	2003/02/13
ļ <sup>—</sup>	101	7027120.0015.	US-PGPUB;	13:37
			EPO; JPO;	13.37
			DERWENT;	
			IBM TDB	
_	3372	((test or tests or testing or tester or	USPAT;	2003/02/13
	3372	tested or testers) and ("circuit board"	US-PGPUB;	13:41
ļ		or "circuit boards" or pcb)).ti.	EPO; JPO;	13.41
		or cricuit boards or peb//.cr.	DERWENT;	
			IBM TDB	
_	114	((test or tests or testing or tester or	USPAT;	2003/02/13
_	114	tested or testers) and ("circuit board"	US-PGPUB;	14:18
		or "circuit boards" or pcb)).ti. and	EPO; JPO;	14.10
		(heat or heats or heating or heated or	DERWENT;	
		heater or heater or temperature or	IBM TDB	
			1551-155	
l _	32	temperatures).ab. 4792683.URPN.	USPAT	2003/02/13
	32	1,52,003. OREM.	VSEAT	13:55
l _	150	324/703.ccls.	USPAT;	2003/02/13
[	150	July 100.0020.	US-PGPUB;	14:19
			EPO; JPO;	
			DERWENT;	
			IBM TDB	
l _	476	324/760.ccls.	USPAT;	2003/02/13
	1,0	021, 700.0013.	US-PGPUB;	14:20
			EPO; JPO;	
			DERWENT;	
			IBM TDB	
_	150	702/99.ccls.	USPAT;	2003/02/13
	130	, , , , , , , , , , , , , , , , , , , ,	US-PGPUB;	14:20
			EPO; JPO;	- 1 - 2 - 0
			DERWENT;	
			IBM TDB	į
_	504	702/130.ccls.	USPAT;	2003/02/13
	304	102/130.0013.	US-PGPUB;	14:21
				14.21
			EPO; JPO; DERWENT;	
I	I	I	IBM_TDB	i l

		,		
-	60	702/133.ccls.	USPAT;	2003/02/13
			US-PGPUB;	14:21
			EPO; JPO;	
	1			
1	i		DERWENT;	
	İ		IBM_TDB	
-	61	702/134.ccls.	USPAT;	2003/02/13
			US-PGPUB;	14:21
				1 1 1 1 2 1
			EPO; JPO;	
Į			DERWENT;	
1	ļ		IBM TDB	
l _	38	702/135.ccls.	USPAT;	2003/02/13
		702,130.0015.	US-PGPUB;	14:21
			1	14:21
			EPO; JPO;	
	İ		DERWENT;	1
			IBM TDB	
	237	702/136.ccls.	USPAT;	2003/02/13
-	231	702/136.0018.	4	1
			US-PGPUB;	14:21
			EPO; JPO;	
			DERWENT;	
		700/117 1-	IBM_TDB	1 2002 (22
-	493	702/117.ccls.	USPAT;	2003/02/13
			US-PGPUB;	15:55
	[		EPO; JPO;	
			DERWENT;	
	1			
			IBM_TDB	/
-	16	l · · · ·	USPAT;	2003/02/13
	1	heater or heated or heaters or heating or	US-PGPUB;	15:59
		temperature or temperatures or degree or	EPO; JPO;	
		degrees).ab.	DERWENT;	
	1		IBM_TDB	
_	1045	(702/118.ccls. 702/119.ccls.	USPAT;	2003/02/13
	1	702/120.ccls. 324/703.ccls. 324/760.ccls.	US-PGPUB;	16:20
		702/99.ccls. 702/130.ccls. 702/133.ccls.	EPO; JPO;	
		702/134.ccls. 702/135.ccls.	DERWENT;	
		702/136.ccls.) and (heat or heats or	IBM_TDB	
		heater or heated or heaters or heating or	<del>-</del>	
		temperature or temperatures or degree or		
		degrees).ab.		
	_			0000 (00 (10
-	5		USPAT;	2003/02/13
		702/120.ccls.) and (heat or heats or	US-PGPUB;	16:01
		heater or heated or heaters or heating or	EPO; JPO;	
	1	temperature or temperatures or degree or	DERWENT;	1
	1		_	
		degrees).ab.	IBM_TDB	l
-	116	, , ,	USPAT;	2003/02/13
		heater or heated or heaters or heating or	US-PGPUB;	16:02
		temperature or temperatures or degree or	EPO; JPO;	
		degrees).ab.		
	1	dedrees).an.	DERWENT;	
		l	IBM_TDB	
-	399	(702/130.ccls.) and (heat or heats or	USPAT;	2003/02/13
		heater or heated or heaters or heating or	US-PGPUB;	16:02
		temperature or temperatures or degree or	EPO; JPO;	
			l .	
		degrees).ab.	DERWENT;	
			IBM_TDB	
-	47	(702/133.ccls.) and (heat or heats or	USPAT;	2003/02/13
		heater or heated or heaters or heating or	US-PGPUB;	16:02
		temperature or temperatures or degree or	ì	
			EPO; JPO;	
		degrees).ab.	DERWENT;	
	1		IBM_TDB	
-	51	(702/134.ccls.) and (heat or heats or	USPAT;	2003/02/13
	1	heater or heated or heaters or heating or	US-PGPUB;	16:02
	1		j .	1 10.02
	1	temperature or temperatures or degree or	EPO; JPO;	
	1	degrees).ab.	DERWENT;	
	1		IBM TDB	
l _	35	(702/135.ccls.) and (heat or heats or	USPAT;	2003/02/13
	33			
İ	1	heater or heated or heaters or heating or	US-PGPUB;	16:02
		temperature or temperatures or degree or	EPO; JPO;	
		degrees).ab.	DERWENT;	
	1			
Ļ	l		IBM_TDB	

_	102	(702/136.ccls.) and (heat or heats or heater or heated or heaters or heating or temperature or temperatures or degree or degrees).ab.	USPAT; US-PGPUB; EPO; JPO; DERWENT;	2003/02/13 16:02
-	78	(324/703.ccls.) and (heat or heats or heater or heated or heaters or heating or temperature or temperatures or degree or	IBM_TDB USPAT; US-PGPUB; EPO; JPO;	2003/02/13 16:02
_	276	degrees).ab.  (324/760.ccls.) and (heat or heats or heater or heated or heaters or heating or temperature or temperatures or degree or degrees).ab.	DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2003/02/13 16:10
_	191		IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 17:26
_	83407		USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/02/13 17:27
_	164	((resistance or resistances or resistor or resistors or resistivity or resistivities) near3 surface) same bus	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/02/13 17:28
_	51	(US-4576322-\$ or US-6215323-\$ or US-4251336-\$ or US-4956605-\$ or US-4706010-\$ or US-6229329-\$ or US-6300862-\$ or US-6469497-\$ or US-6438821-\$ or US-6437634-\$ or US-6362721-\$ or US-6288597-\$ or US-6278313-\$ or US-6104274-\$ or US-5852445-\$ or US-5801612-\$ or US-5852445-\$ or US-5801612-\$ or US-5302022-\$ or US-5130644-\$ or US-5302022-\$ or US-5130644-\$ or US-5182629-\$ or US-5696450-\$ or US-5543727-\$ or US-5696450-\$ or US-5543727-\$ or US-5733041-\$ or US-6360935-\$ or US-5733041-\$ or US-6360935-\$ or US-5733041-\$ or US-6140825-\$ or US-5733041-\$ or US-6140825-\$ or US-5760595-\$ or US-6422741-\$ or US-6369987-\$ or US-5760595-\$ or US-6428981-\$ or US-5760595-\$ or US-6428981-\$ or US-5698987-\$ or US-5760595-\$ or US-6428981-\$ or US-5657394-\$).did. or (EP-408863-\$ or US-5657394-\$).did. or (JP-04144248-\$ or JP-04104072-\$ or JP-01286322-\$ or JP-06347500-\$ or JP-03255966-\$ or JP-01046638-\$).did. or (NN81092167).tban.	USPAT; EPO; JPO; IBM_TDB	2003/02/13 17:31

		1 / / vo 4576200 A CO15000 A		1 0000 /00 /10
-	5	((US-4576322-\$ or US-6215323-\$ or	USPAT;	2003/02/13
		US-4251336-\$ or US-4956605-\$ or	US-PGPUB;	17:31
		US-4706010-\$ or US-6229329-\$ or	EPO; JPO;	
		US-6300862-\$ or US-6469497-\$ or	DERWENT;	ŀ
		US-6438821-\$ or US-6437634-\$ or	IBM_TDB	1
		US-6362721-\$ or US-6288597-\$ or	_	
		US-6278313-\$ or US-6104274-\$ or		
		US-5852445-\$ or US-5801612-\$ or		
	-	US-6215324-\$ or US-4734641-\$ or		
		US-5302022-\$ or US-5130644-\$ or		
		US-3982218-\$ or US-6238086-\$ or		
		US-5182629-\$ or US-5696450-\$ or		
1		US-5543727-\$ or US-5172063-\$).did. or		
1		(US-4792683-\$ or US-6422741-\$ or		
	•	1 •		
1		US-6360935-\$ or US-5733041-\$ or		
		US-5006788-\$ or US-5392219-\$ or		
		US-6140825-\$ or US-5760595-\$ or		
		US-5698987-\$ or US-5260668-\$ or		
		US-RE32625-\$ or US-4739258-\$ or		ŀ
		US-6329831-\$ or US-5451885-\$ or		
		US-4483629-\$ or US-5657394-\$).did. or		
		(EP-408863-\$ or EP-283778-\$).did. or		
	1	(JP-04144248-\$ or JP-04104072-\$ or		
		JP-01286322-\$ or JP-06347500-\$ or		
		JP-03255966-\$ or JP-01046638-\$).did. or		
	1	(NN81092167).tban.) and "power bus"		
_	118	"bus resistance"	USPAT;	2003/02/21
		W	US-PGPUB;	08:39
į			EPO; JPO;	
	·		DERWENT;	
			IBM TDB	
_	2	("bus resistance" or "bus resistances")	USPAT;	2003/02/21
1	_	with (temperature or temperatures)	US-PGPUB;	08:40
ŀ		with (temperature of temperatures)	EPO; JPO;	00.40
			1	
			DERWENT;	
	0.4	/ !! have and the mall and !! have and the mall !! have the	IBM_TDB	2002/02/21
-	94	,	USPAT;	2003/02/21
		(temperature or temperatures)	US-PGPUB;	08:41
			EPO; JPO;	
			DERWENT;	
		4500 000 45004	IBM_TDB	/
-	32	4792683.URPN.	USPAT	2003/02/21
				08:56
-	4	, , , , , , , , , , , , , , , , , , , ,	USPAT	2003/02/21
		"4647220").PN.		08:56
-	6	4380725.URPN.	USPAT	2003/02/21
	1			09:02
-	0	6426484.URPN.	USPAT	2003/02/21
			1	09:09
	21	("4256945"   "4448306"   "4623401"	USPAT	2003/02/21
	1	"4695713"   "4701587"   "4717814"		09:09
		"4745264"   "4769525"   "4792683"		
	1	"5010233"   "5117279"   "5175409"		
		"5194695"   "5239806"   "5418189"		
	1	"5498899"   "5500555"   "5521426"		
		"5598031"   "5938956"   "6111220").PN.		]
_	1 0	6422741.URPN.	USPAT	2003/02/21
				09:10
_	13	("4679946"   "4792683"   "4866276"	USPAT	2003/02/21
	13	"5111048"   "5228776"   "5562345"	331.21	09:10
		"5574379"   "5698978"   "5706094"		"".1"
				1
		"5748003"   "5886534"   "5952561"		
	_	"6173604").PN.	HEDATE	2002/02/21
1	0	6360935.URPN.	USPAT	2003/02/21
	L		İ	09:11

-	28	("4227415"   "4409333"   "4467638"   "4657169"   "4657196"   "4696104"   "4792683"   "4941256"   "5089700"	USPAT	2003/02/21 09:11
		"5118945"   "5148375"   "5206705"     "5208528"   "5246291"   "5250809"		
		"5262022"   "5357346"   "5401380"     "5407275"   "5425859"   "5446549"		
		"5574801"   "5676302"   "5836504"		
		"5912984"   "5963662"   "5971249"     "5988487").PN.		
-	6	("voltage drop" with temperature) same epoxy	USPAT; US-PGPUB; EPO; JPO; DERWENT;	2003/02/21 09:18
_	347	(voltage with temperature) same epoxy	IBM_TDB USPAT;	2003/02/21
			US-PGPUB; EPO; JPO; DERWENT;	09:19
_	109	(voltage with temperature) with epoxy	IBM_TDB USPAT;	2003/02/21
			US-PGPUB; EPO; JPO; DERWENT;	09:41
-	21	5246291.URPN.	IBM_TDB USPAT	2003/02/21
_	5	("3803413"   "4792683"   "4999499"	USPAT	09:20 2003/02/21
_		"5052816"   "5064291").PN.		09:20
-	19	5963662.URPN.	USPAT	2003/02/21 09:32
_	2	("3795918"   "5115475").PN.	USPAT	2003/02/21 09:32
-	2	5836504.URPN.	USPAT	2003/02/21 09:36
-	5	"5561696"   "5592562").PN.	USPAT	2003/02/21 09:36
_	83832	short-circuit or short-circuits or short-circuited or short-circuiting	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/02/21
_	1094	(short-circuit or short-circuits or short-circuited or short-circuiting) with (solder or epoxy)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/02/21 09:42
_	232	<pre>((short-circuit or short-circuits or short-circuited or short-circuiting) with (solder or epoxy)) same (heat or heats or heating or heated or temperature or temperatures)</pre>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/02/21 10:23
-	36	(((short-circuit or short-circuits or short-circuited or short-circuiting) with (solder or epoxy)) same (heat or heats or	USPAT; US-PGPUB; EPO; JPO;	2003/02/21 10:23
		heating or heated or temperature or temperatures)) and (test or tests or testing or tested or tester or testers)	DERWENT; IBM_TDB	
-	196	short-circuited or short-circuiting) with (solder or epoxy)) same (heat or heats or heating or heated or temperature or temperatures)) not (((short-circuit or short-circuits or short-circuited or	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 09:58
		short-circuiting) with (solder or epoxy)) same (heat or heats or heating or heated or temperature or temperatures)) and		
		<pre>(test or tests or testing or tested or tester or testers))</pre>		

_	169768	short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or	USPAT; US-PGPUB; EPO; JPO;	2003/02/21
_	112	"short circuited" or "short circuiting" (((short-circuit or short-circuits or	DERWENT; IBM_TDB USPAT;	2003/02/21
		short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuits" or "short circuiting")	US-PGPUB; EPO; JPO;	10:33
		"short circuited" or "short circuiting") with (solder or epoxy)) same (heat or heats or heating or heated or temperature or temperatures)) and (test or tests or	DERWENT; IBM_TDB	
_	567	testing or tested or tester or testers) ((short-circuit or short-circuits or short-circuited or short-circuiting or	USPAT; US-PGPUB;	2003/02/21 11:32
		"short circuit" or "short circuits" or "short circuited" or "short circuiting") with (solder or epoxy)) same (heat or heats or heating or heated or temperature	EPO; JPO; DERWENT; IBM_TDB	
_	576	short-circuited or short-circuiting or "short circuit" or "short circuits" or	USPAT; US-PGPUB; EPO; JPO;	2003/02/21 10:29
		"short circuited" or "short circuiting") with (solder or epoxy)) same (heat or heats or heating or heated or temperature or temperatures)) not (((short-circuit or	DERWENT; IBM_TDB	
		short-circuits or short-circuited or short-circuiting) with (solder or epoxy)) same (heat or heats or heating or heated		
_	76	or temperature or temperatures)) ((((short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or	USPAT; US-PGPUB; EPO; JPO;	2003/02/21 10:24
		"short circuited" or "short circuiting") with (solder or epoxy)) same (heat or heats or heating or heated or temperature or temperatures)) and (test or tests or	DERWENT; IBM_TDB	
		testing or tested or tester or testers)) not ((((short-circuit or short-circuits or short-circuited or short-circuiting)		
		with (solder or epoxy)) same (heat or heats or heating or heated or temperature or temperatures)) and (test or tests or testing or tested or tester or testers))		
_	575	1	USPAT; US-PGPUB; EPO; JPO; DERWENT;	2003/02/23 14:28
		with (solder or epoxy)) same (heat or heats or heating or heated or temperature or temperatures)) not (((short-circuit or short-circuits or short-circuited or	IBM_TDB	
		short-circuiting) with (solder or epoxy)) same (heat or heats or heating or heated or temperature or temperatures))) not		
		<pre>(((((short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting")</pre>		
		with (solder or epoxy)) same (heat or heats or heating or heated or temperature or temperatures)) and (test or tests or testing or tested or tester or testers))		
		not ((((short-circuit or short-circuits or short-circuited or short-circuiting) with (solder or epoxy)) same (heat or		
		heats or heating or heated or temperature or temperatures)) and (test or tests or testing or tested or tester or testers)))		

_	2	("4,851,946").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/02/21 10:28
-	335	<pre>(((short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting") with (solder or epoxy)) same (heat or heats or heating or heated or temperature or temperatures)) not (((short-circuit or short-circuits or short-circuited or short-circuiting) with (solder or epoxy)) same (heat or heats or heating or heated or temperature or temperatures))</pre>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 10:29
-	301	(((bridging or bridge or bridges or bridged) with (solder or epoxy)) same (heat or heats or heating or heated or temperature or temperatures)) and (test or tests or testing or tested or tester or testers)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 10:40
-	15	(((bridging or bridge or bridges or bridged) with (solder or epoxy)) same (heat or heats or heating or heated or temperature or temperatures)) and (test or tests or testing or tested or tester or testers or monitor or monitors or monitoring or monitored or determine or determining or determines or determination or determinations).ti.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 10:41
_	0	<pre>((short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting") with (solder or epoxy)) same ("surface temperature")</pre>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 11:33
-	0	<pre>((short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting") with (solder or epoxy)) same ("surface resistance")</pre>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 11:34
-	3254	UNISYS.asn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/02/21 11:36
-	36	UNISYS.asn. and (short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/02/21 11:42
-	2	("4938410").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/02/21 13:07
-		("1949716"   "3752642"   "4757800"   "4771929").PN.	USPAT	2003/02/21 11:43
_	253	"high acceleration stress test" or hast	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 11:50

-	2	("high acceleration stress test" or "highly accelerated stress test" or "high acceleration stress tests" or "highly accelerated stress tests" or hast) with (short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 11:54
-	3	("high acceleration stress test" or "highly accelerated stress test" or "highly accelerated stress tests" or "highly accelerated stress tests" or "high acceleration saturation test" or "high acceleration saturation tests" or "highly accelerated saturation tests" or "highly accelerated saturation tests" or hast) same (short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 11:56
-	118	"burn-in" same (short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 11:57
-	513	((test or testing or tests or tester or testers) and (solder or soldering or solders)).ti.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/02/21 13:17
-	4	((test or testing or tests or tester or testers) and (solder or soldering or solders)).ti. and "heat sink"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 13:11
-	105	<pre>((test or testing or tests or tester or testers) and (solder or soldering or solders)).ti. and (temperature or temperatures or heat or heats or heating or heated).ab.</pre>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/02/21 13:15
-	4	("6323663 <sup>"</sup> ).PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/02/21 13:15
-	100	<pre>((short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting") and (solder or soldering or solders)).ti.</pre>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 13:19
-	945	("integrated circuit" or "integrated circuts" or "ic" or "ics" or "ic's") and peltier	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/02/21 17:09
-	187	("integrated circuit" or "integrated circuts" or "ic" or "ics" or "ic's") and peltier and (fan or fans)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/02/21 17:14
-	29	("integrated circuit" or "integrated circuts" or "ic" or "ics" or "ic's" or "circuit boards" or "pcb") and peltier and (fan or fans) and ((temperature or temperatures) with (ramp or ramping or ramps or ramped))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 17:15

[-	4	5760595.URPN.	USPAT	2003/02/23
				13:31
-	4	5760595.URPN.	USPAT	2003/02/23
	0	"shorts test".ti.	USPAT;	13:32   2003/02/23
-	١	shorts test .tr.	US-PGPUB;	13:34
			EPO; JPO;	13.34
			DERWENT;	
			IBM TDB	i l
_	75	"shorts test"	USPAT;	2003/02/23
			US-PGPUB;	13:39
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
-	27	"shorts test" and (temperature or	USPAT;	2003/02/23
		temperatures or heat or heats or heating	US-PGPUB;	13:55
		or heated)	EPO; JPO; DERWENT;	
			IBM TDB	
<b> </b> _	2	("4938410").PN.	USPAT;	2003/02/23
1	_	( 4550 110 / .TM.	US-PGPUB;	13:56
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
-	2	("4938410").PN.	USPAT;	2003/02/23
			US-PGPUB;	13:56
			EPO; JPO;	
			DERWENT;	
	8	//!/4029/10!!\ am /!!E1720/2!!\ am	IBM_TDB USPAT;	2003/02/23
-	0	(("4938410") or ("5172063") or ("5696450") or ("5543727")).PN.	US-PGPUB;	13:57
		( 3090430 ) OI ( 3343727 )).FN.	EPO; JPO;	13.37
			DERWENT;	
			IBM TDB	
_	0	(short-circuit or short-circuits or	USPAT;	2003/02/23
		short-circuited or short-circuiting or	US-PGPUB;	14:30
		"short circuit" or "short circuits" or	EPO; JPO;	
		"short circuited" or "short circuiting")	DERWENT;	
		with bus with ground with (resistance or	IBM_TDB	
		resistances) with (plot or plots or		
	1	plotting or plotted or plotting or graph or graphs or graphing or graphed or		
		graphs)		
_	4	, , ,	USPAT;	2003/02/23
	_	short-circuited or short-circuiting or	US-PGPUB;	14:29
		"short circuit" or "short circuits" or	EPO; JPO;	
		"short circuited" or "short circuiting")	DERWENT;	
		with bus with ground with (resistance or	IBM_TDB	
	_	resistances)		0000 (00 (00
-	0	, ,	USPAT;	2003/02/23
		short-circuited or short-circuiting or   "short circuit" or "short circuits" or	US-PGPUB; EPO; JPO;	14:30
	ŀ	"short circuit" or "short circuits" or "short circuiting")	DERWENT;	
		same (bus with ground with (resistance or	IBM TDB	
		resistances) with (plot or plots or		
		plotting or plotted or plotting or graph		
		or graphs or graphing or graphed or		
		graphs))		
-	10	(short-circuit or short-circuits or	USPAT;	2003/02/23
		short-circuited or short-circuiting or	US-PGPUB;	14:32
		"short circuit" or "short circuits" or	EPO; JPO;	
		"short circuited" or "short circuiting")	DERWENT;	
		same (bus with ground with (resistance or resistances))	IBM_TDB	
_	14370	((short-circuit or short-circuits or	USPAT;	2003/02/23
	133,0	short-circuited or short-circuiting or	US-PGPUB;	14:34
		"short circuit" or "short circuits" or	EPO; JPO;	
	1	"short circuited" or "short circuiting")	DERWENT;	
		with (detect or detects or detecting or	IBM_TDB	
		detected or detection or detections))		

-	969	((short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting") with (detect or detects or detecting or detected or detection or detections)) with (resistance or resistances or resitivity)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/23 14:36
-	0	<pre>(((short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting") with (detect or detects or detecting or detected or detection or detections)) with (resistance or resistances or resitivity)) same "power bus"</pre>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/23 14:36
_	12		USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/23 14:37
_	19	<pre>(((short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting") with (detect or detects or detecting or detected or detection or detections)) with (resistance or resistances or resitivity)) same ("circuit board" or "circuit boards" or pcb)</pre>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/23 14:45
_	2	("5844330").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/02/23 16:06
_	2	("6140825").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/02/23 14:46
-	2	("5,419,780").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT;	2003/02/23 15:03
_	2	("6140825").PN.	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2003/02/23 16:08
-	2	("4739258").PN.	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2003/02/23 16:38
-	2	("4739258").PN.	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2003/02/23 16:53
_	2	("5419780").PN.	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/23 17:10

[-	2	("6226994").PN.	USPAT;	2003/02/23
			US-PGPUB;	17:16
			EPO; JPO;	
1			DERWENT;	}
			IBM_TDB	
<b> </b> -	1	("re 32625").PN.	USPAT;	2003/02/23
			US-PGPUB;	17:16
			EPO; JPO;	
			DERWENT;	
	İ		IBM_TDB	
-	2	("5419780").PN.	USPAT;	2003/02/24
			US-PGPUB;	08:23
			EPO; JPO;	
1			DERWENT;	
			IBM_TDB	